


<b>Search Notes</b>  	<b>Application/Control No.</b>  10597443	<b>Applicant(s)/Patent Under Reexamination</b>  NAKAMURA ET AL.
	<b>Examiner</b>  Sean Basquill	<b>Art Unit</b>  1612

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
See STN search history	7/27/2009	SB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--